

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				ATTY DOCKET NO. 03500.014384.		APPLICATION NO. 09/506,289	
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				APPLICANT MASAFUMI KYOGAKU ET AL.			
Date Submitted to PTO: [DATE]				FILING DATE FEBRUARY 18, 2004		GROUP 2818	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>MAF</i>		6,626,719	9/03	Ono et al.	445	24	<u> </u>
<i>MAF</i>		6,288,494	9/01	Tsukamoto et al.	315	169.1	<u> </u>
<i>MAF</i>		6,472,814	10/02	Yamanobe	313	495	<u> </u>
<i>MAF</i>		6,184,610	2/01	Shibata et al.	313	309	<u> </u>
<i>MAF</i>		6,246,168	6/01	Kishi et al.	313	495	<u> </u>
<i>MAF</i>		5,532,544	7/96	Yoshioka et al.	313	310	<u> </u>
<i>MAF</i>		5,986,389	11/99	Tsukamoto	313	310	<u> </u>
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
		HO9-35620	2/97	Japan	<u> </u>	<u> </u>	Abstract
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
<i>MAF</i>		Fukano, Y., et al., Scanning Force/Tunneling Microscopy as a Novel Technique for the Study of nanometer-Scale Dielectric Breakdown of Silicon Oxide Layer, Jpn. J. Appl. Phys. Vol. 32 (1993) pp. 290-293, Part 1, No 1B, January 1993					
EXAMINER <i>MAF</i>				DATE CONSIDERED <i>8-19-05</i>			

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PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)ATTY DOCKET NO.
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MASAFUMI KYOGAKU ET AL.FILING DATE
February 18, 2000

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U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
MB	6,169,356	1/2/01	Ohnishi et al.	313	495	6/23/94	

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	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO OR ABSTRACT	
MB	8-264112	10/11/96	Japan			Abstract	
MB	8-162015	6/21/96	Japan			Abstract	
MB	9-27268	1/28/97	Japan			Abstract	
MB	9-27272	1/28/97	Japan			Abstract	
MB	10-3848	1/6/98	Japan			Abstract	
MB	10-3847	1/6/98	Japan			Abstract	
MB	10-3853	1/6/98	Japan			Abstract	
MB	10-3854	1/6/98	Japan			Abstract	
EP	0 701 265 B1	3/13/96	EPO				

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	W.P. Dyke et al., "Field Emission", Advances in Electronics and Electron Physics, Vol. VIII, 1956, pp. 89-185.	
MB	H. Araki, et al., "Electroforming and Electron Emission of Carbon Thin Films", Journal of the Vacuum Soc. of Japan, Vol. 2-6, No. 1, 1983, pp. 22-29 (with English Abstract on p. 22).	
MB	G. Dittmer, "Electrical Conduction and Electron Emission of Discontinuous Thin Films", Thin Solid Films, 9, 1972 pp. 317-328.	
MB	M. Elinson, et al. "The Emission of Hot Electrons and the Field Emissions of Electrons From Tin Oxide", Radio Engineering and Electronic Physics, July 1965, pp. 1290-1298.	
AMINER	René K. Shaw	DATE CONSIDERED 5/21/01

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U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
MAP	5,645,462	7/8/97	Banno et al.	445	51	—	

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DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT		
MAP	64-19657	1/89	JAPAN	—	Abstract		

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OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)	

EXAMINER <i>MAP</i>	DATE CONSIDERED <i>1/6/03</i>
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